

FDS6673BZ

P-Channel PowerTrench® MOSFET

-30V, -14.5A, 7.8mΩ

General Description

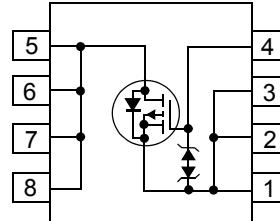
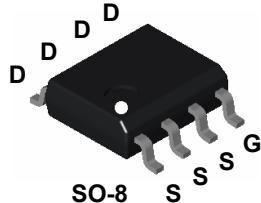
This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench process that has been especially tailored to minimize the on-state resistance.

This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.



Features

- Max $r_{DS(on)} = 7.8\text{m}\Omega$, $V_{GS} = -10\text{V}$, $I_D = -14.5\text{A}$
- Max $r_{DS(on)} = 12\text{m}\Omega$, $V_{GS} = -4.5\text{V}$, $I_D = -12\text{A}$
- Extended V_{GS} range (-25V) for battery applications
- HBM ESD protection level of 6.5kV typical (note 3)
- High performance trench technology for extremely low $r_{DS(on)}$
- High power and current handling capability
- RoHS compliant



MOSFET Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Ratings | Units |
|----------------|--|------------|-------|
| V_{DS} | Drain to Source Voltage | -30 | V |
| V_{GS} | Gate to Source Voltage | ± 25 | V |
| I_D | Drain Current -Continuous | (Note1a) | A |
| | -Pulsed | -75 | A |
| P_D | Power Dissipation for Single Operation | (Note1a) | 2.5 |
| | | (Note1b) | 1.2 |
| | | (Note1c) | 1.0 |
| T_J, T_{STG} | Operating and Storage Temperature | -55 to 150 | °C |

Thermal Characteristics

| | | | |
|-----------------|--|----|------|
| $R_{\theta JA}$ | Thermal Resistance , Junction to Ambient (Note 1a) | 50 | °C/W |
| $R_{\theta JC}$ | Thermal Resistance , Junction to Case (Note 1) | 25 | °C/W |

Package Marking and Ordering Information

| Device Marking | Device | Reel Size | Tape Width | Quantity |
|----------------|-----------|-----------|------------|------------|
| FDS6673BZ | FDS6673BZ | 13" | 12mm | 2500 units |

Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|-----------------------------------|---|--|-----|----------|-----|----------------------------|
| Off Characteristics | | | | | | |
| B_{VDSS} | Drain to Source Breakdown Voltage | $I_D = -250\mu\text{A}, V_{GS} = 0\text{V}$ | -30 | | | V |
| ΔB_{VDSS} ΔT_J | Breakdown Voltage Temperature Coefficient | $I_D = -250\mu\text{A}$, referenced to 25°C | | -20 | | $\text{mV}/^\circ\text{C}$ |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = -24\text{V}, V_{GS} = 0\text{V}$ | | -1 | | μA |
| I_{GSS} | Gate to Source Leakage Current | $V_{GS} = \pm 25\text{V}, V_{DS} = 0\text{V}$ | | ± 10 | | μA |

On Characteristics (Note 2)

| | | | | | | |
|--|--|--|----|------|-----|----------------------------|
| $V_{GS(\text{th})}$ | Gate to Source Threshold Voltage | $V_{GS} = V_{DS}, I_D = -250\mu\text{A}$ | -1 | -1.9 | -3 | V |
| $\Delta V_{GS(\text{th})}$ ΔT_J | Gate to Source Threshold Voltage Temperature Coefficient | $I_D = -250\mu\text{A}$, referenced to 25°C | | 8.1 | | $\text{mV}/^\circ\text{C}$ |
| $r_{DS(\text{on})}$ | Drain to Source On Resistance | $V_{GS} = -10\text{V}, I_D = -14.5\text{A}$ | | 6.5 | 7.8 | $\text{m}\Omega$ |
| | | $V_{GS} = -4.5\text{V}, I_D = -12\text{A}$ | | 9.6 | 12 | |
| | | $V_{GS} = -10\text{V}, I_D = -14.5\text{A}$ $T_J = 125^\circ\text{C}$ | | 9.7 | 12 | |
| g_{FS} | Forward Transconductance | $V_{DS} = -5\text{V}, I_D = -14.5\text{A}$ | | 60 | | S |

Dynamic Characteristics

| | | | | | | |
|-----------|------------------------------|---|--|------|------|----|
| C_{iss} | Input Capacitance | $V_{DS} = -15\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$ | | 3500 | 4700 | pF |
| C_{oss} | Output Capacitance | | | 600 | 800 | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 600 | 900 | pF |

Switching Characteristics (Note 2)

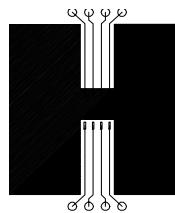
| | | | | | | |
|---------------------|----------------------------|--|--|------|-----|----|
| $t_{d(\text{on})}$ | Turn-On Delay Time | $V_{DD} = -15\text{V}, I_D = -1\text{A}$ $V_{GS} = -10\text{V}, R_{GS} = 6\Omega$ | | 14 | 26 | ns |
| t_r | Rise Time | | | 16 | 29 | ns |
| $t_{d(\text{off})}$ | Turn-Off Delay Time | | | 225 | 36 | ns |
| t_f | Fall Time | | | 105 | 167 | ns |
| Q_g | Total Gate Charge | $V_{DS} = -15\text{V}, V_{GS} = -10\text{V}, I_D = -14.5\text{A}$ | | 88 | 124 | nC |
| Q_g | Total Gate Charge | $V_{DS} = -15\text{V}, V_{GS} = -5\text{V}, I_D = -14.5\text{A}$ | | 46 | 65 | nC |
| Q_{gs} | Gate to Source Gate Charge | | | 8 | | nC |
| Q_{gd} | Gate to Drain Charge | | | 23.5 | | nC |

Drain-Source Diode Characteristics

| | | | | | | |
|----------|---------------------------------------|---|--|------|------|----|
| V_{SD} | Source to Drain Diode Forward Voltage | $V_{GS} = 0\text{V}, I_S = -2.1\text{A}$ | | -0.7 | -1.2 | V |
| t_{rr} | Reverse Recovery Time | $I_F = 14.5\text{A}, di/dt = 100\text{A}/\mu\text{s}$ | | | 45 | ns |
| Q_{rr} | Reverse Recovery Charge | $I_F = 14.5\text{A}, di/dt = 100\text{A}/\mu\text{s}$ | | | 34 | nC |

Notes:

1: R_{thJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{thJC} is guaranteed by design while R_{thCA} is determined by the user's board design.



a) $50^\circ\text{C}/\text{W}$ (10 sec)
when mounted on a 1 in^2
pad of 2 oz copper

b) $105^\circ\text{C}/\text{W}$ when mounted
on a $.04\text{ in}^2$ pad of 2 oz
copper

c) $125^\circ\text{C}/\text{W}$ when mounted
on a minimum pad

Scale 1 : 1 on letter size paper

2: Pulse Test: Pulse Width < $300\mu\text{s}$, Duty Cycle < 2.0%.

3: The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

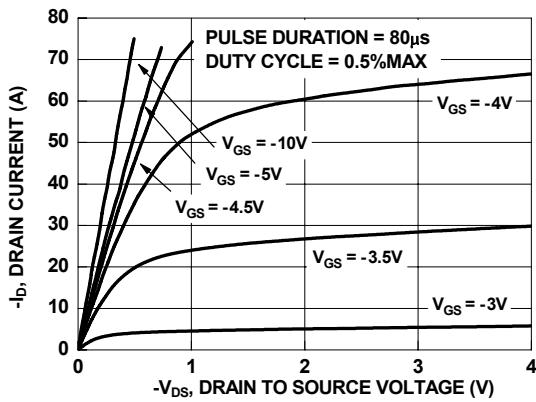


Figure 1. On Region Characteristics

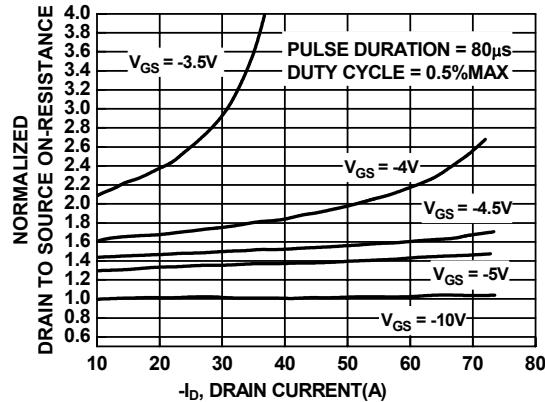


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

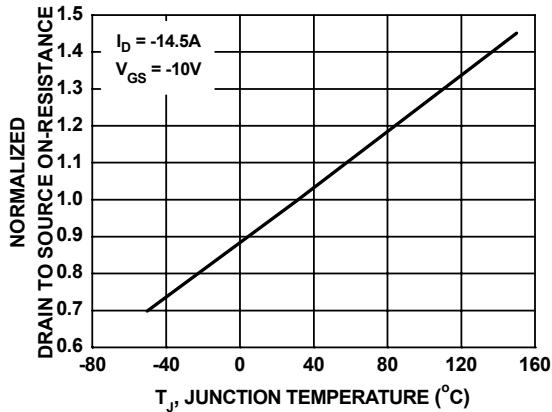


Figure 3. Normalized On Resistance vs Junction Temperature

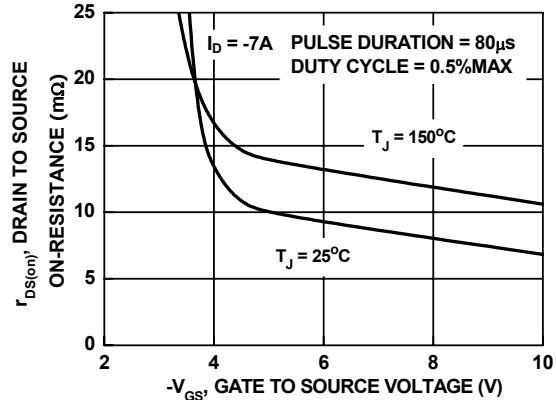


Figure 4. On-Resistance vs Gate to Source Voltage

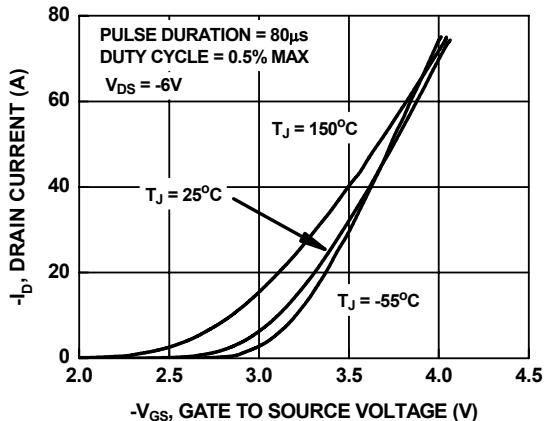


Figure 5. Transfer Characteristics

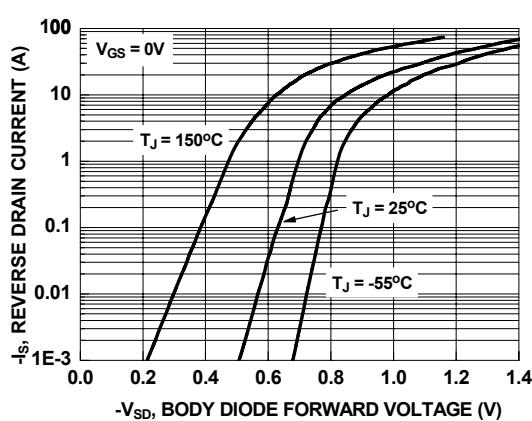


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

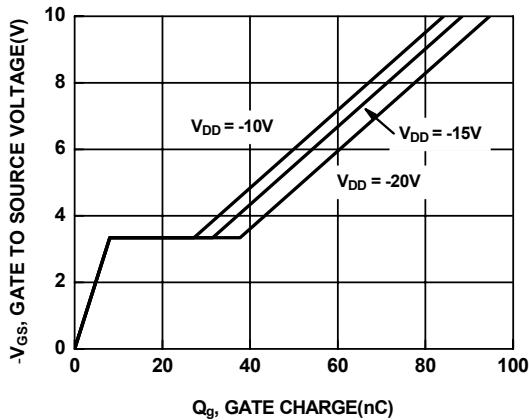


Figure 7. Gate Charge Characteristics

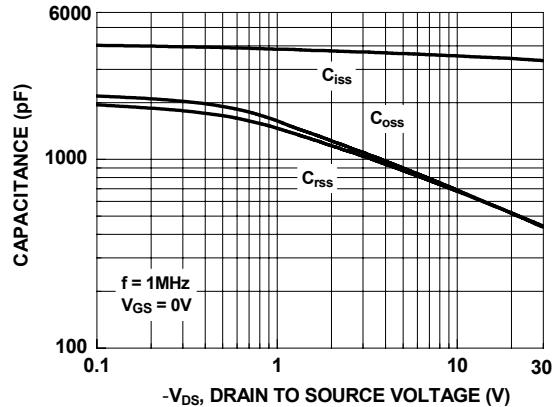


Figure 8. Capacitance vs Drain to Source Voltage

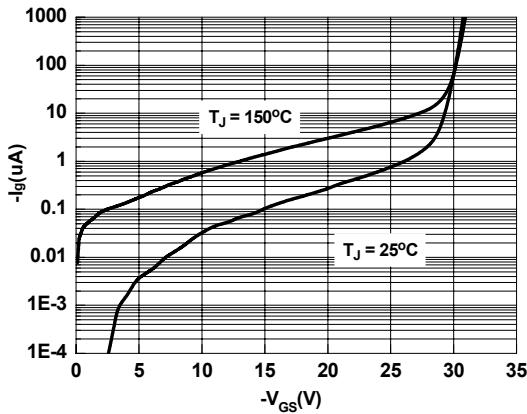


Figure 9. I_g vs V_{GS}

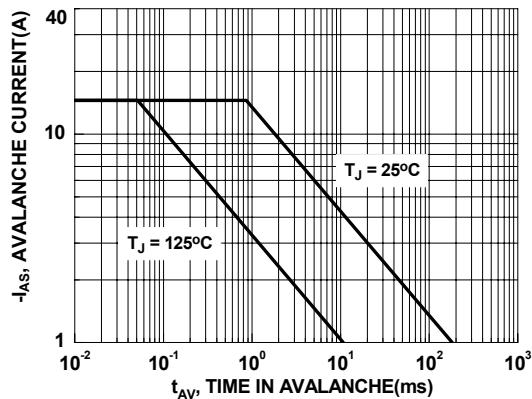


Figure 10. Unclamped Inductive Switching Capability

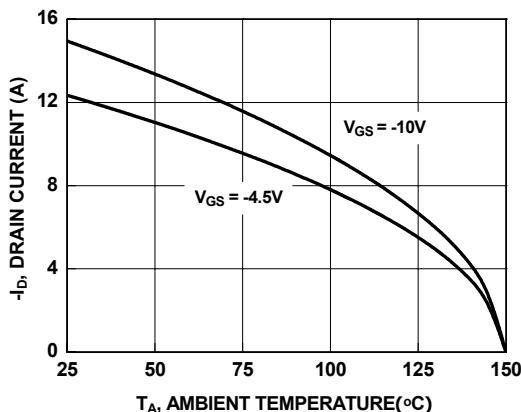


Figure 11. Maximum Continuous Drain Current vs Ambient Temperature

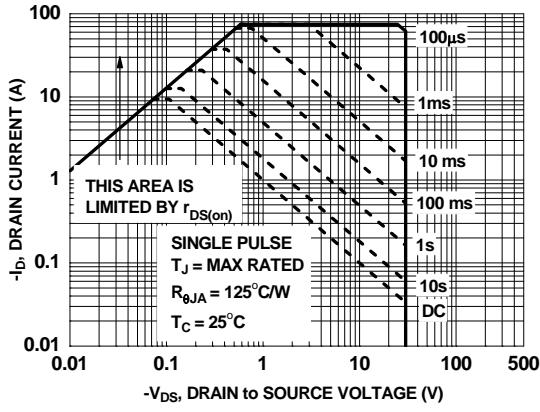


Figure 12. Forward Bias Safe Operating Area

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

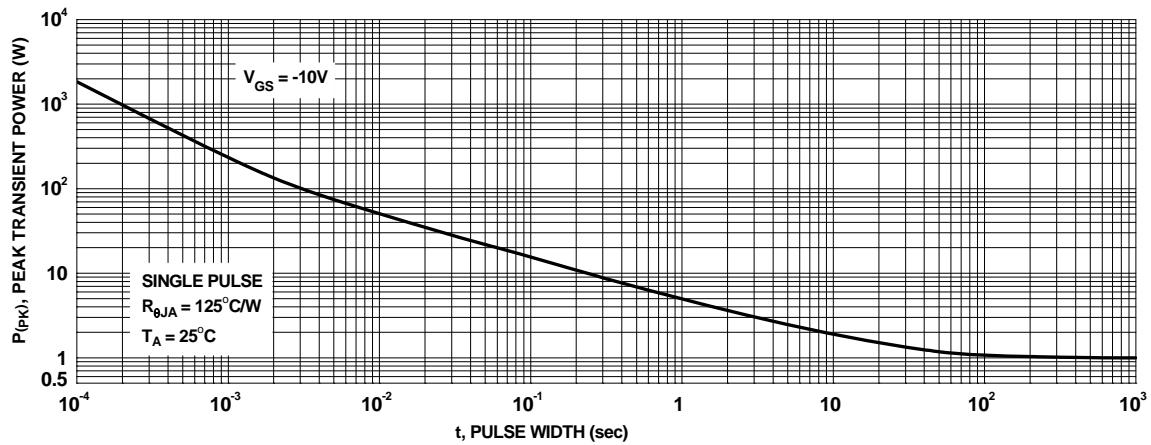


Figure 13. Junction-to-Case Transient Thermal Response Curve

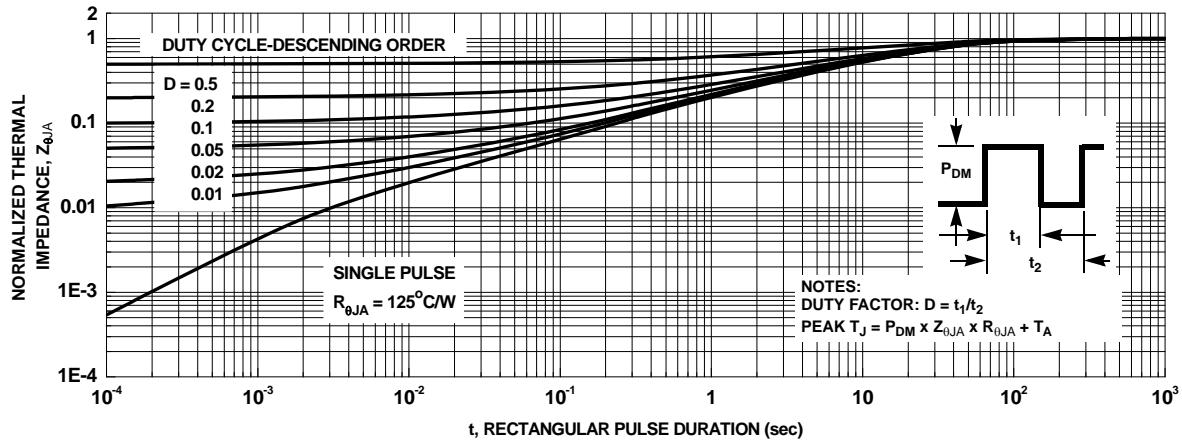


Figure 14. Junction-to-Ambient Transient Thermal Response Curve



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